

ATTACHMENT A: SEARCH HISTORY

L Number	Hits	Search Text	DB	Time stamp
17	158	(test same device) and (trench same capacitor) and DRAM	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/14 11:09
18	32	((test same device) and (trench same capacitor) and DRAM) and (parallel same capacitor\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/14 11:08
19	5	((test same device) and (trench same capacitor) and DRAM) and (parallel same capacitor\$1)) and (scribe same line)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/14 11:08
20	29	((test same device) and (trench same capacitor) and DRAM) and (first same transistor) and (second same transistor) and (bit same contact)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/14 11:09
21	393	test and (trench same capacitor) and DRAM	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/14 11:20
22	5	(test and (trench same capacitor) and DRAM) and (((test same device) and (trench same capacitor) and DRAM) and (parallel same capacitor\$1)) and (scribe same line))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/14 11:21
23	27	(test and (trench same capacitor) and DRAM) and scribe	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/14 11:22
24	3	((test and (trench same capacitor) and DRAM) and scribe) and 365/\$7.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/14 11:22
25	1	("6529427" "2002/0142539" "2003/0003611").PN.	USPAT	2004/06/14 11:23
26	0	6693834.URPN.	USPAT	2004/06/14 11:23
27	1	("6529427" "2002/0142539" "2003/0003611").PN.	USPAT	2004/06/14 11:23